



IN THE
UNITED STATES PATENT AND TRADEMARK OFFICE

APPLICANTS: Steven W. Meeks and Rusmin Kudinar
SERIAL NO.: 09/347,622
FILING DATE: July 2, 1999
TITLE: System for Simultaneously Measuring Thin Film Layer Thickness, Reflectivity, Roughness, Surface Profile and Magnetic Pattern
EXAMINER: Unknown
GROUP ART UNIT: 2877
ATTY. DKT. NO.: 20830-04304; 4304 US

CERTIFICATE OF MAILING

I hereby certify that this correspondence is being deposited with the United States Postal Service as first class mail in an envelope addressed to: Commissioner for Patents, Washington, D.C. 20231 on the date shown below.

Dated: 22 Dec 2000

By: John T. McNelis
John T. McNelis, Reg. No. 37,186

COMMISSIONER FOR PATENTS
WASHINGTON, D.C. 20231

PRELIMINARY AMENDMENT "A"

Sir:

Before examining the application, please enter and consider this preliminary amendment.

It is not believed that extensions of time are required beyond those which may otherwise be provided for in documents accompanying this Amendment. However, in the event that additional extensions of time are necessary to prevent abandonment of this application, then such

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01 FC:202 80.00 OP
02 FC:203 108.00 OP

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J. McInella
1/27/01
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